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**( Not for submission under 37 CFR 1.99)**

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| Application Number | 10568814 |
| Filing Date | 2006-09-06 |
| First Named Inventor | Jose Carlos Ortiz Aleman |
| Art Unit | |
| Examiner Name | |
| Attorney Docket Number | 50992 |

**U.S.PATENTS**

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| **INFORMATION DISCLOSURE STATEMENT BY APPLICANT** *(use as many sheets as necessary)* | | | | Application Number | 10/568,814 |
| | | | | Filing Date | February 21, 2006 |
| | | | | First Named Inventor | Jose Carlos Ortiz Aleman |
| | | | | Art Unit | |
| | | | | Examiner Name | |
| Sheet | 1 | of | 1 | Attorney Docket Number | 50992 |

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